P-Channel Enhancement Mode Power MOSFET

Description

The HM4421B uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge .This device is well suited for high current load applications.

General Features

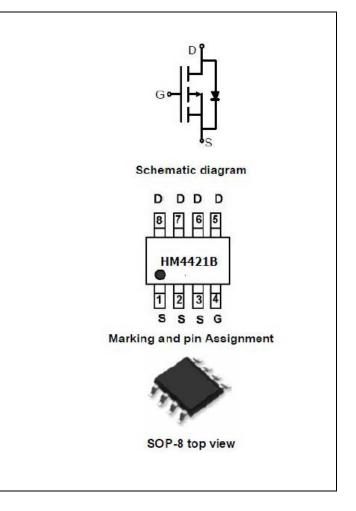
- V_{DS} =-60V, I_{D} =-6.5A $R_{DS(ON)}$ <45m Ω @ V_{GS} =-10V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

Load switch

100% UIS TESTED!

100% ΔVds TESTED!



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM4421B	HM4421B	SOP8	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	-60	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	-6.5	Α
Drain Current-Continuous(T _C =100 °C)	I _D (100℃)	-4.5	А
Pulsed Drain Current	I _{DM}	-6.5	А
Maximum Power Dissipation	P _D	3	W
Derating factor		0.76	W/℃
Single pulse avalanche energy (Note 5)	E _{AS}	722	mJ
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 150	$^{\circ}$ C

Thermal Characteristic

ſ	Thormal Posistance, Junction to Caso (Note 2)	D	1 21	°C/W
	Thermal Resistance, Junction-to-Case(Note 2)	ReJC	1.31	C/VV

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Electrical Characteristics (T_C=25 ℃ unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics	<u>.</u>		•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-60	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-60V,V _{GS} =0V	-	-	-1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{D}=-250\mu A$	-2.0	-2.9	-3.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D =-6.5A	-	39	45	mΩ
Forward Transconductance	g FS	V _{DS} =-10V,I _D =-6.5A	-	25	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C _{lss})/ 05)/)/ 0)/	-	6460	-	PF
Output Capacitance	C _{oss}	V _{DS} =-25V,V _{GS} =0V,	-	719	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	535	-	PF
Switching Characteristics (Note 4)		,	· ·	Į.		
Turn-on Delay Time	t _{d(on)}		-	15	-	nS
Turn-on Rise Time	t _r	V_{DD} =-30V, R_L =1.5 Ω ,	-	17	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =-10V, R_{G} =3 Ω	-	40	-	nS
Turn-Off Fall Time	t _f		-	45	-	nS
Total Gate Charge	Qg	V 001 054	-	75		nC
Gate-Source Charge	Q _{gs}	V _{DS} =-30,I _D =-6.5A,	-	16		nC
Gate-Drain Charge	Q_{gd}	V _{GS} =-10V	-	19		nC
Drain-Source Diode Characteristics			1			
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =-6.5A	-		-1.2	V
Diode Forward Current (Note 2)	Is		-	-	-6.5	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF =- 6.5A	-	50		nS
Reverse Recovery Charge	Qrr	di/dt = -100A/µs(Note3) - 59			nC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

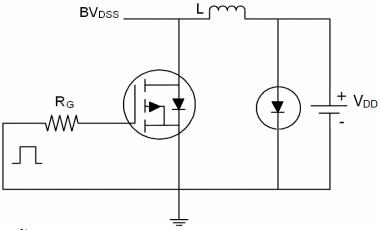
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width ≤ 300μ s, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- **5.** E_{AS} condition: Tj=25 $^{\circ}$ C,V_{DD}=-20V,V_G=-10V,L=1mH,Rg=25 Ω ,I_{AS}=38A

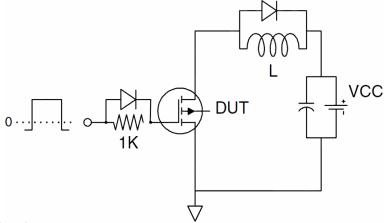
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Test Circuit

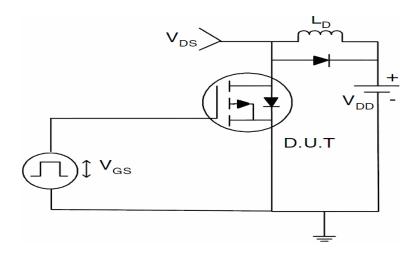
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit

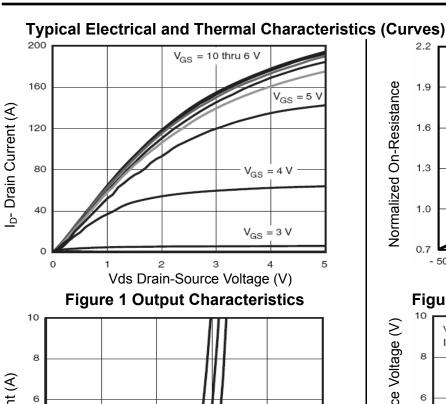


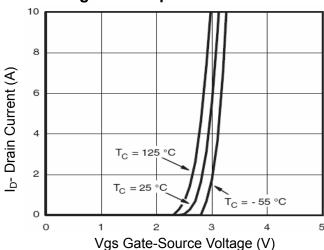
3) Switch Time Test Circuit

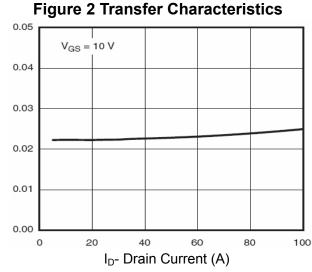


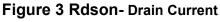
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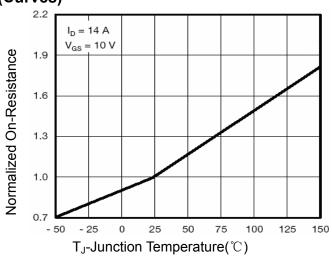
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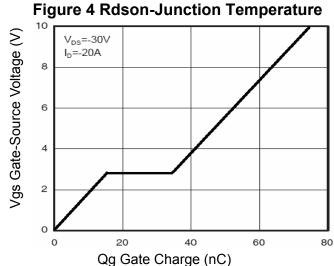












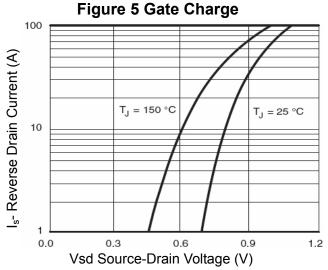


Figure 6 Source- Drain Diode Forward

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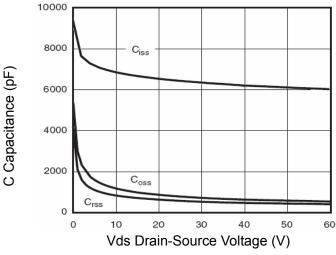


Figure 7 Capacitance vs Vds

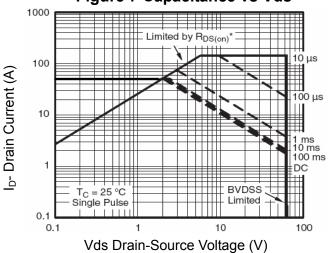
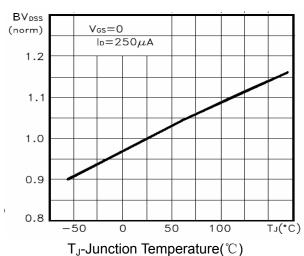


Figure 8 Safe Operation Area



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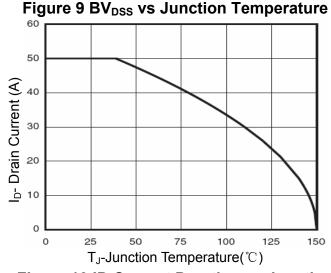


Figure 10 ID Current Derating vs Junction Temperature

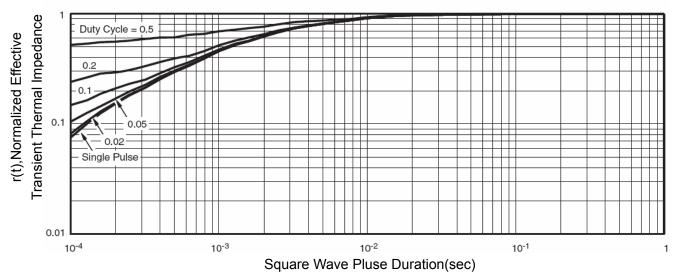
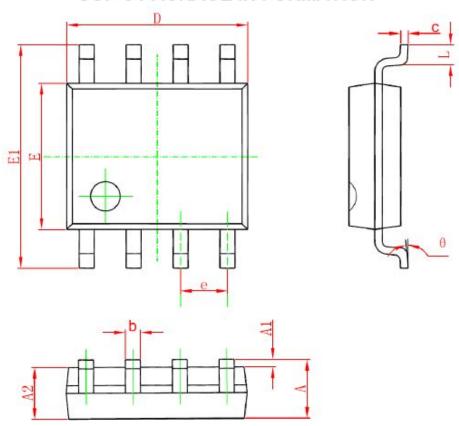


Figure 11 Normalized Maximum Transient Thermal Impedance

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SOP-8 PACKAGE IN FORMATION



C: made al	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	0.483 TYP.		0.190 TYP.		
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114	TYP.	
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063	TYP.	
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350	TYP.	0.211 TYP.		

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